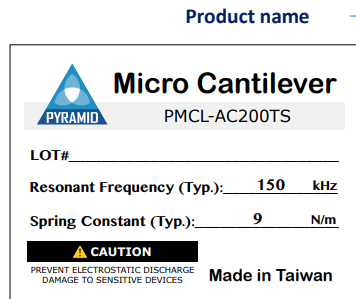


Micro Cantilever

Product name

PMCL-AC200TS

Silicon AFM probe with a sharpened tetrahedral tip



Product name

PMCL – AC200TS

PMCL: Pyramid Micro Cantilever

AC: Tapping mode measurement

200: Cantilever length of 200 um

T: Sharpened tetrahedral tip

S: Reflex coating (Aluminum)

Specification

Material

Micro Cantilever Tip & lever	Silicon (n-type, 0.01 – 0.02 ohm.cm)
Metal coating (tip side)	None
Metal coating (reflex side)	Aluminum on Silicon cantilever
Chip	Silicon (n-type, 0.01 – 0.02 ohm.cm)

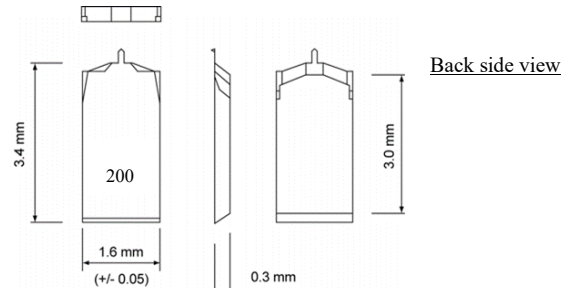
Chip

A rectangular shape silicon probe on one side of the silicon chip

Dimension

Front side view

Tip side view

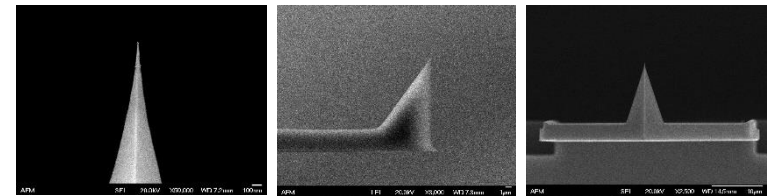


Probe Tip

The probe tip is a sharpened tetrahedral. The tip is fabricated on the exact end of each probe.

Dimensions

	Typ. Value	Typ. Range
Tip height (um)	14	9 - 19
Tip radius (nm)	7	4 - 10
Probe tip half angle (deg.)	(axis) less than 17.5 (side) less than 17.5	
Probe side tip angle (deg.)	(front) 0, (back) 35. (side) 18, 18	

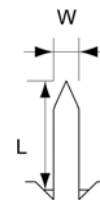


Cantilever

Calculated mechanical properties

	Typical value	Typical range
Resonant frequency (kHz)	150	100 - 200
Spring constant (N/m)	9	2.8 - 21

Dimensions



Cantilever length L (um)	200 (±20)
Cantilever width W (um)	40 (±2)
Cantilever thickness t (um)	3.5 (±0.6)
Cantilever thickness t _m (um)	Aluminum 0.1 (±0.04)

